	<b>Analysis Report - 2000-13153</b>			
	<b>Customer Name:</b>	SAMPLE REPORT-15	<b>Purchase Order:</b>	4504435317
	<b>Part Number:</b>	S29GL256S11TFIV10	<b>Lot/Date Code:</b>	1521
	<b>Manufacturer:</b>	SPANSION	<b>Devices Received:</b>	50

## Summary Of Inspection Results

**Results Summary**  
 With respect to the observation of anomalies or evidence of counterfeiting, no inconsistencies were found with the lot or test samples during the inspection.

Test-Process Operation	Quantity Inspected	Pass	Fail	Date	N/A	Comments / Observations
Documentation and Packaging (SAE AS6081, 4.2.6.4.1) (Non-destructive)						
Condition Observed	50	50	0	2015-08-18		Devices were received in acceptable condition. Total 50 devices, date code 1521.
External Visual Inspection (SAE AS6081)(Non-destructive)						
Condition Observed	50	50	0	2015-08-20		50 devices from date code 1521 were visually inspected. No anomalies were found. Devices passed visual inspection.
Package Inspection (SAE AS6081)(Non-destructive)						
Dimensions	1	1	0	2015-08-18		Dimensions match datasheet specification 56 Pin TSOP
Re-Marking / Re-Surfacing Testing (SAE AS6081)						
Solvent Test for Re-Surfacing - Acetone (Destructive)	1	1	0	2015-08-20		Acetone test was performed on 1 device with date code 1521. No secondary coating was removed during this process. Device passed acetone testing.
Solvent Test for Re-Surfacing - Heat Solvent (Destructive)	1	1	0	2015-08-20		HST (Heated Solvent Test) was performed on 1 device from date code 1521 using Dynasolve 750 solution. No secondary coating was removed during this process. Device passed HST testing.
Delid/Decapsulation Internal Analysis (AS6081 4.2.6.4.6)(Destructive)						
Die Verification	1	1	0	2015-08-20		Internal inspection was performed on 1 device with date code 1521. Device revealed Spansion logo with 2010 copyright. Die marking 98223A was also found.
X-Ray Inspection (SAE AS6081 4.2.6.4.4)(Non-destructive)						
Internal Construction	5	5	0	2015-08-20		5 samples of date code 1521 were X-ray. Die construction and size are all the same. No anomalies were found.
XRF Inspection (SAE AS6081 4.2.6.4.5)(Non-destructive)						
RoHS Compliant	3	3	0	2015-08-20		3 Samples of 1521 date code were checked for RoHS Compliance. Devices are RoHS compliant with Pb level > 1000ppm.
Electrical Test (MIL-STD-883 and Manufacturer Specification)(Non-destructive)						
Memory Function Test TA = 25°C	20	20	0	2015-08-19		S29GL256S11TFIV10: NOR Flash Parallel 3V/3.3V 256M-bit 16M x 16 110ns 56-Pin TSOP Tested 20 functionally at 25C via Memory Test: Read, Verify, and Blank Check. Passed: 20. Checksum: FE000000. Sample Programming was performed and Part's erased afterwards at 25C.
<b>Equipment Used</b>	PROGRAMMER <b>Asset Tag:</b> 42 <b>Calibration Due Date:</b> Not Required					
Solderability Test (MIL-STD-883 Method 203.8 and J-STD-002)(Destructive)						

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### Analysis Report - 2000-13153

<b>Customer Name:</b>	SAMPLE REPORT-15	<b>Purchase Order:</b>	4504435317
<b>Part Number:</b>	S29GL256S11TFIV10	<b>Lot/Date Code:</b>	1521
<b>Manufacturer:</b>	SPANSION	<b>Devices Received:</b>	50

Hot Solder Dip	1	1	0	2015-08-20	1 device from date code 1521 was tested using dip and look method. Device was inspected under 20X magnification. All leads indicated to have over 95% solder coverage. No pinholes or voids are found.
----------------	---	---	---	------------	--

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	<b>Analysis Report - 2000-13153</b>			
	<b>Customer Name:</b>	SAMPLE REPORT-15	<b>Purchase Order:</b>	4504435317
	<b>Part Number:</b>	S29GL256S11TFIV10	<b>Lot/Date Code:</b>	1521
	<b>Manufacturer:</b>	SPANSION	<b>Devices Received:</b>	50

Documentation and Packaging (SAE AS6081, 4.2.6.4.1) (Non-destructive)

**Results Summary**

Devices were received in acceptable condition. Total 50 devices, date code 1521.

Criteria	Acceptable	Suspect	Not Acceptable	N/A	Comments / Observations
Incoming Conditions					
ESD Protection	X				
Poor Syntax or Alterations	X				
Correct MSL Packaging	X				MSL 3
Quantity Match Document	X				
Box Damaged	X				
Type of Package	X				

**Images For Documentation and Packaging .**

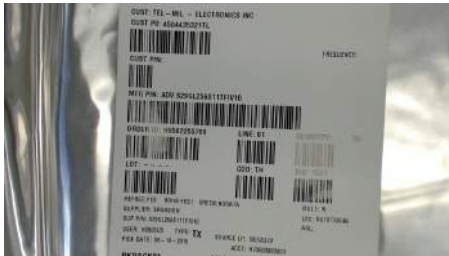


Figure 1. INCOMING

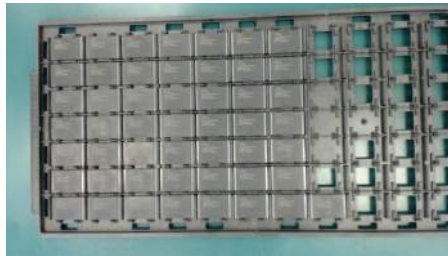


Figure 2. INCOMING



Figure 3. INCOMING

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### Analysis Report - 2000-13153

<b>Customer Name:</b>	SAMPLE REPORT-15	<b>Purchase Order:</b>	4504435317
<b>Part Number:</b>	S29GL256S11TFIV10	<b>Lot/Date Code:</b>	1521
<b>Manufacturer:</b>	SPANSION	<b>Devices Received:</b>	50

#### External Visual Inspection (SAE AS6081 or MIL-STD-883, Method 2009.9)(Non-destructive)

#### Results Summary

50 devices from date code 1521 were visually inspected. No anomalies were found. Devices passed visual inspection.

Criteria	Acceptable	Suspect	Not Acceptable	N/A	Comments / Observations
External Conditions					
Markings - Top	X				SPANSION S29GL256S11TFIV1 521BB076 A □10 SPANSION
Markings - Bottom				X	
Pin 1 Cavity - Top	X				
Country of Origin	X				Thailand
Body Residue	X				None was found
Construction Quality	X				Acceptable
Lead / BGA Conditions					
Lead Alignment	X				Acceptable
Lead Formation / Scratches	X				Acceptable
Lead Missing Pins	X				None was found
Lead Plating Composition	X				Acceptable
Lead Excessive or Uneven Plating	X				Acceptable
Lead Discoloration, Dirt or Residue	X				None was found
Lead Oxidation	X				None was found
BGA Solder Mask Damage				X	
BGA Oxidation				X	
BGA Scratches In The Mask				X	
BGA Debris or Residue Between Solder Spheres				X	
BGA Missing				X	
BGA Damage				X	

#### Images For External Visual Inspection.

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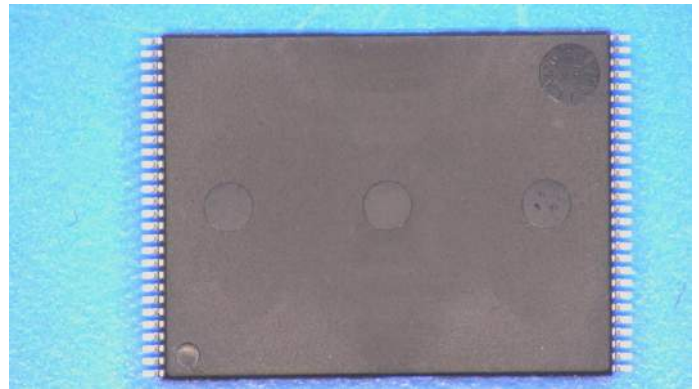


### Analysis Report - 2000-13153

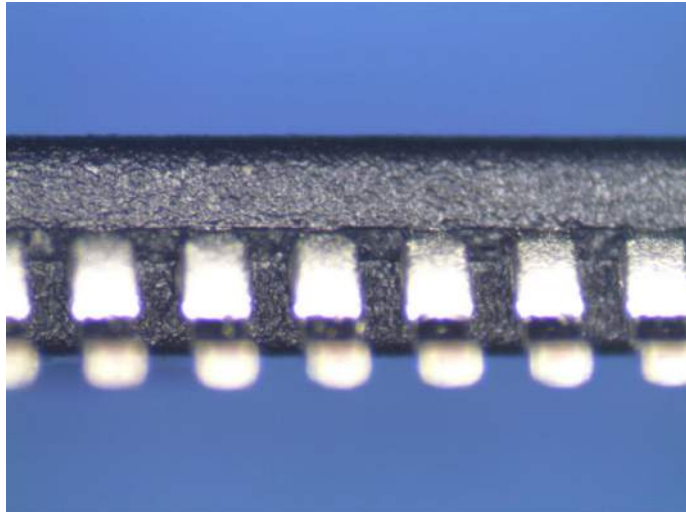
<b>Customer Name:</b>	SAMPLE REPORT-15	<b>Purchase Order:</b>	4504435317
<b>Part Number:</b>	S29GL256S11TFIV10	<b>Lot/Date Code:</b>	1521
<b>Manufacturer:</b>	SPANSION	<b>Devices Received:</b>	50



**Figure 4. TOP**



**Figure 5. BOTTOM**



**Figure 6. SIDE**



**Figure 7. TOP PIN**

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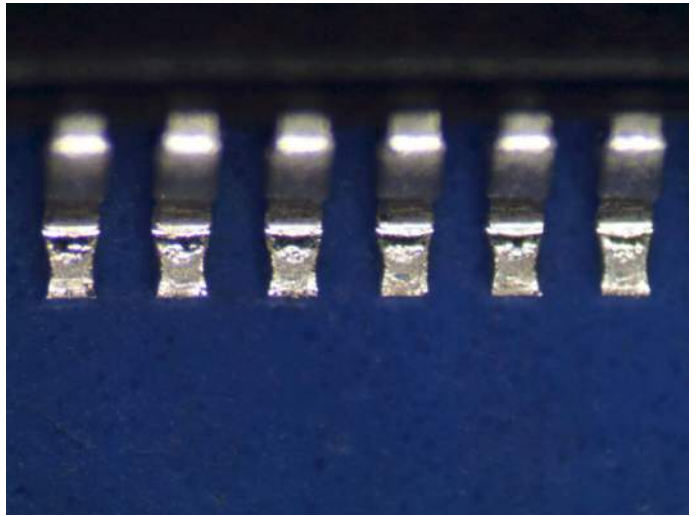


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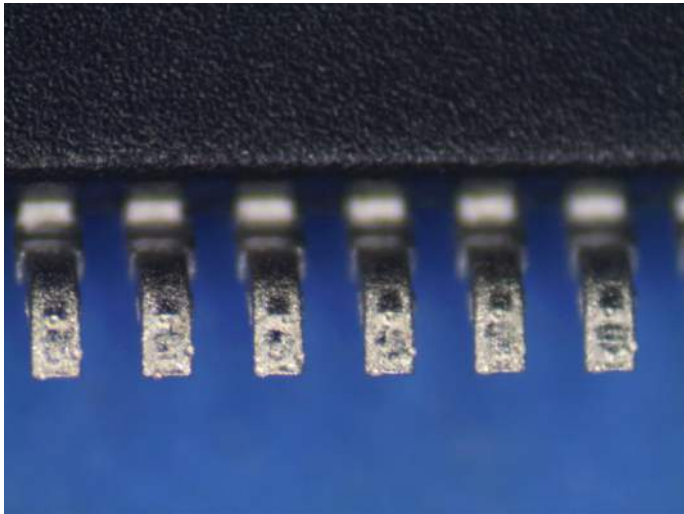
<b>Customer Name:</b>	SAMPLE REPORT-15	<b>Purchase Order:</b>	4504435317
<b>Part Number:</b>	S29GL256S11TFIV10	<b>Lot/Date Code:</b>	1521
<b>Manufacturer:</b>	SPANSION	<b>Devices Received:</b>	50



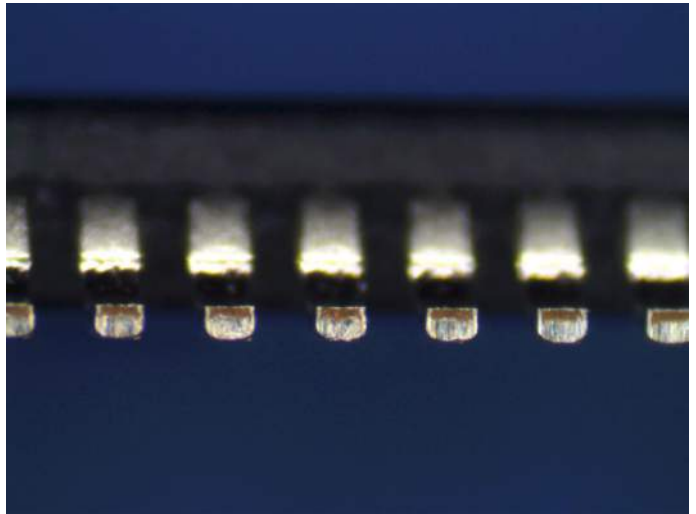
**Figure 8.** BOTTOM PIN



**Figure 9.** LEADS VIEW 1



**Figure 10.** LEADS VIEW 2



**Figure 11.** LEAD ENDS

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<b>Part Number:</b>	S29GL256S11TFIV10	<b>Lot/Date Code:</b>	1521
<b>Manufacturer:</b>	SPANSION	<b>Devices Received:</b>	50

#### Device Package

#### Results Summary

L=20.02mm, W=14.05mm, Thickness=1.15mm

Criteria	Acceptable	Suspect	Not Acceptable	N/A	Comments / Observations
Package Dimensions					
Dimensions	X				

#### Images For Device Package.



**Figure 12.** LENGTH



**Figure 13.** WIDTH



**Figure 14.** THICKNESS

#### Images For Device Package. (Continued From Previous Page)

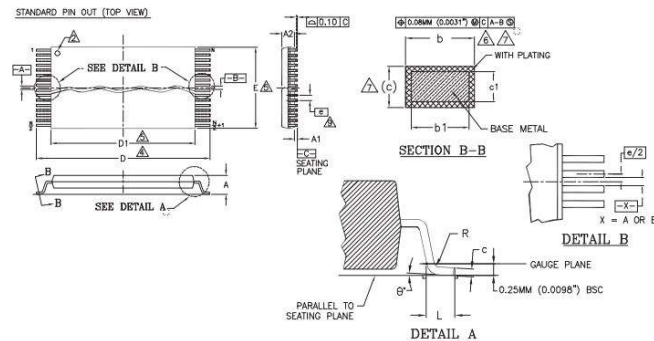
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<b>Part Number:</b>	S29GL256S11TFIV10	<b>Lot/Date Code:</b>	1521
<b>Manufacturer:</b>	SPANSION	<b>Devices Received:</b>	50

**Figure 11.2 56-Pin Thin Small Outline Package (TSOP), 14 x 20 mm**



PACKAGE	TS 56		
JEDEC	MO-142 (B) EC		
SYMBOL	MIN.	NOM.	MAX.
A	---	---	1.20
A1	0.05	---	0.15
A2	0.95	1.00	1.05
b1	0.17	0.20	0.23
b	0.17	0.22	0.27
c1	0.10	---	0.16
c	0.10	---	0.21
D	19.80	20.00	20.20
D1	18.30	18.40	18.50
E	13.90	14.00	14.10
e	0.50 BASIC		
L	0.50	0.60	0.70
ø	0"	-	8"
R	0.08	---	0.20
N	56		


- NOTES:**
- △ CONTROLLING DIMENSIONS ARE IN MILLIMETERS (mm). (DIMENSIONING AND TOLERANCING CONFORMS TO ANSI Y14.5M-1982.)
  - △ PIN 1 IDENTIFIER FOR STANDARD PIN OUT (DIE UP).
  - △ TO BE DETERMINED AT THE SEATING PLANE -C-. THE SEATING PLANE IS DEFINED AS THE PLANE OF CONTACT THAT IS MADE WHEN THE PACKAGE LEADS ARE ALLOWED TO REST FREELY ON A FLAT HORIZONTAL SURFACE.
  - △ DIMENSIONS D1 AND E DO NOT INCLUDE MOLD PROTRUSION. ALLOWABLE MOLD PROTRUSION IS 0.15 mm PER SIDE.
  - △ DIMENSION b DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.08 mm TOTAL IN EXCESS OF DIMENSION AT MAX MATERIAL CONDITION. MINIMUM SPACE BETWEEN PROTRUSION AND AN ADJACENT LEAD TO BE 0.07 mm.
  - △ THESE DIMENSIONS APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN 0.10 mm AND 0.25 mm FROM THE LEAD TIP.
  - △ LEAD COPLANARITY SHALL BE WITHIN 0.10 mm AS MEASURED FROM THE SEATING PLANE.
  - △ DIMENSION "e" IS MEASURED AT THE CENTERLINE OF THE LEADS.

2160208-10A

**Figure 15. PHYSICAL DIMENSIONS**

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	<b>Part Number:</b>	S29GL256S11TFIV10	<b>Lot/Date Code:</b>	1521
	<b>Manufacturer:</b>	SPANSION	<b>Devices Received:</b>	50

Remarking and Resurfacing (SAE AS6081)

Criteria	Acceptable	Suspect	Not Acceptable	N/A	Comments / Observations
Re-Surfacing / Re-Marking Testing (SAE AS6081)					
Solvent Test for Re-Surfacing - Acetone (Destructive)(CAS Registry 67-64-1)	X				Acetone test was performed on 1 device with date code 1521. No secondary coating was removed during this process. Device passed acetone testing.
Solvent Test for Re-Surfacing - Heat Solvent (Destructive) Dynasolve 750	X				HST (Heated Solvent Test) was performed on 1 device from date code 1521 using Dynasolve 750 solution. No secondary coating was removed during this process. Device passed HST testing.

Images For Remarking and Resurfacing.

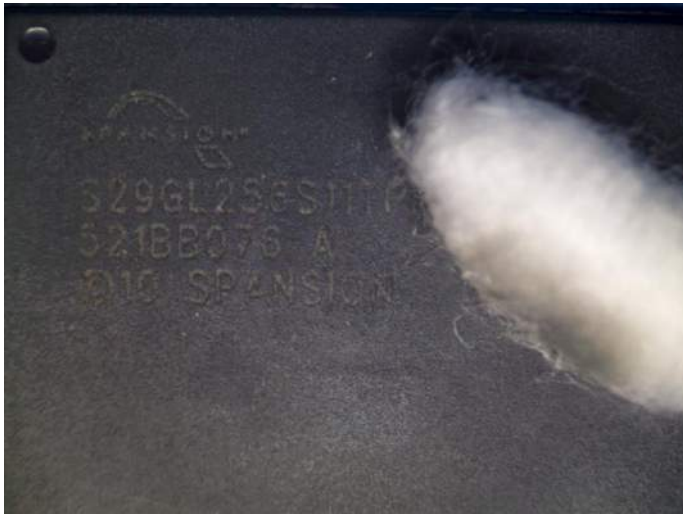



Figure 16. ACETONE



Figure 17. HST

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	<b>Analysis Report - 2000-13153</b>			
	<b>Customer Name:</b>	SAMPLE REPORT-15	<b>Purchase Order:</b>	4504435317
	<b>Part Number:</b>	S29GL256S11TFIV10	<b>Lot/Date Code:</b>	1521
	<b>Manufacturer:</b>	SPANSION	<b>Devices Received:</b>	50

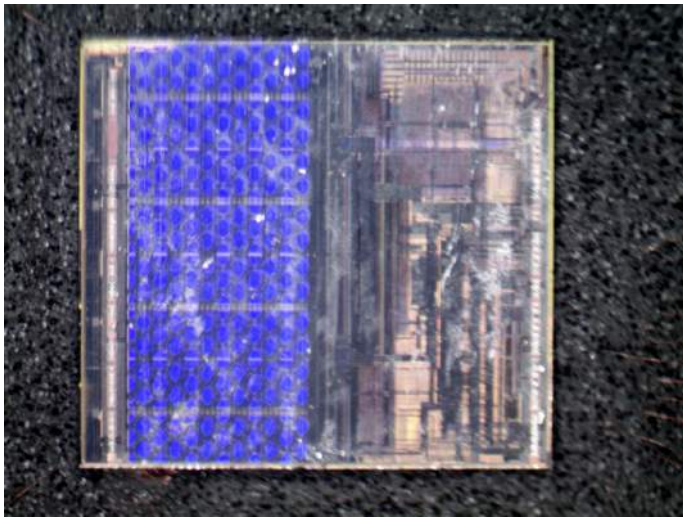
Delid/Decapsulation Internal Analysis (AS6081 4.2.6.4.6) or (MIL-STD-883, Method 2014) (Destructive)

**Results Summary**

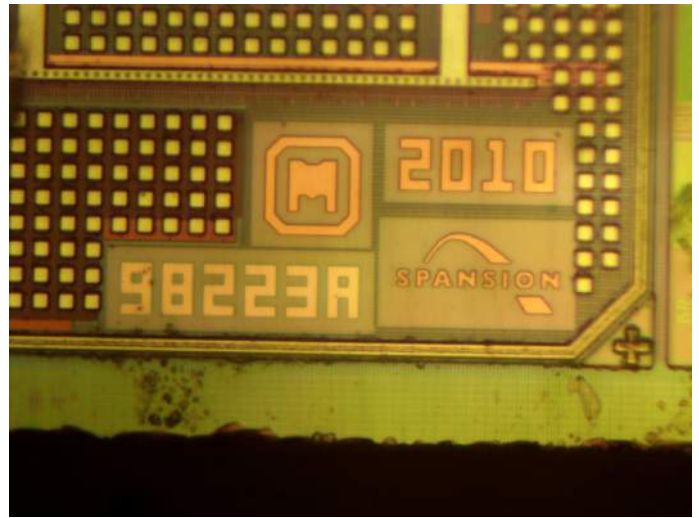
Internal inspection was performed on 1 device with date code 1521. Device revealed Spansion logo with 2010 copyright. Die marking 98223A was also found.

Criteria	Acceptable	Suspect	Not Acceptable	N/A	Comments / Observations
Internal Visual Inspection					
Die Topography	X				
Die Markings	X				

**Images For Delid/Decapsulation Internal Analysis.**



**Figure 18. DIE TOPOGRAPHY**



**Figure 19. DIE MARKING**

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## Analysis Report - 2000-13153

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<b>Part Number:</b>	S29GL256S11TFIV10	<b>Lot/Date Code:</b>	1521
<b>Manufacturer:</b>	SPANSION	<b>Devices Received:</b>	50

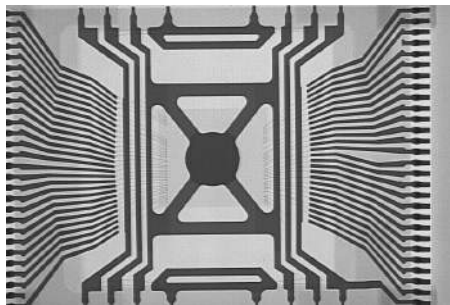
### X-Ray Analysis (SAE AS6081 4.2.6.4.4)(Non-destructive)

#### Results Summary

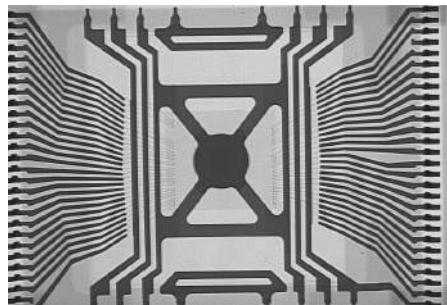
5 samples of date code 1521 were X-ray. Die construction and size are all the same. No anomalies were found.

Criteria	Acceptable	Suspect	Not Acceptable	N/A	Comments / Observations
X-Ray Analysis					
Die Construction	X				
Wire Bond Layout/Quality	X				
Lead Frame Construction	X				

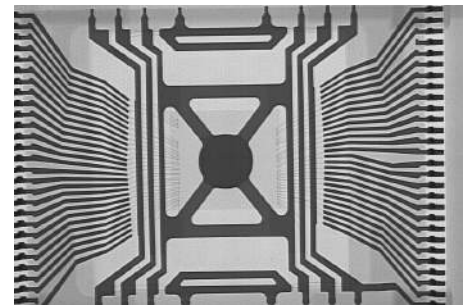
#### Images For X-Ray Analysis.



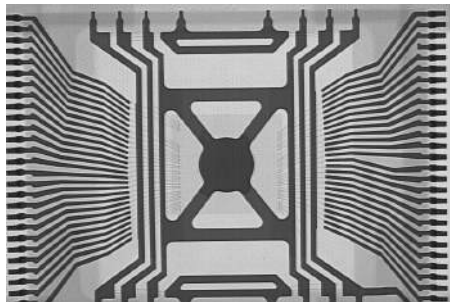
**Figure 20.**  
SO13153-S29GL256S11TFIV10\_000001\_XRAY



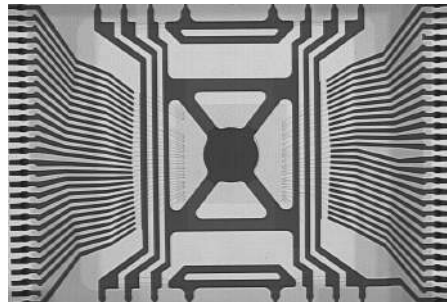
**Figure 21.**  
SO13153-S29GL256S11TFIV10\_000002\_XRAY



**Figure 22.**  
SO13153-S29GL256S11TFIV10\_000003\_XRAY



**Figure 23.**  
SO13153-S29GL256S11TFIV10\_000004\_XRAY



**Figure 24.**  
SO13153-S29GL256S11TFIV10\_000005\_XRAY

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### Analysis Report - 2000-13153

<b>Customer Name:</b>	SAMPLE REPORT-15	<b>Purchase Order:</b>	4504435317
<b>Part Number:</b>	S29GL256S11TFIV10	<b>Lot/Date Code:</b>	1521
<b>Manufacturer:</b>	SPANSION	<b>Devices Received:</b>	50

XRF Analysis (SAE AS6081 4.2.6.4.5)(Non-destructive)

**Results Summary**

3 Samples of 1521 date code were checked for RoHS Compliance. Devices are RoHS compliant with Pb level > 1000ppm.

Criteria	Acceptable	Suspect	Not Acceptable	N/A	Comments / Observations
XRF Analysis					
RoHS Compliance	X				

**Images For XRF Analysis.**

**Test Result**

Part Number	Customer	Date
S29GL256S11TFIV10	TELMIL AN AVNET ISRAEL LTD. DIVISION	08/18/2015

Test Item	Test Result (ppm)			EU RoHS Limit (1000ppm)
	Result 1	Result 2	Result 3	
Lead (Pb)	700	700	800	1000

**Remark:**

(1) ppm = parts per million

\*\*\*\*\*  
\*\*\*\*\*

**Conclusion: Devices are RoHS Compliant**

Lead (Pb)      EU RoHS Directive 2011/65/EU Annex

Pass: RoHS Compliant

\*\*\*\*\*  
\*\*\*\*\*

**Test Method**

Test Item	Test Method	Test Instrument
Pb	X-ray fluorescence	RMD XRF Analyzer

**Figure 25. XRF**

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## Analysis Report - 2000-13153

<b>Customer Name:</b>	SAMPLE REPORT-15	<b>Purchase Order:</b>	4504435317
<b>Part Number:</b>	S29GL256S11TFIV10	<b>Lot/Date Code:</b>	1521
<b>Manufacturer:</b>	SPANSION	<b>Devices Received:</b>	50

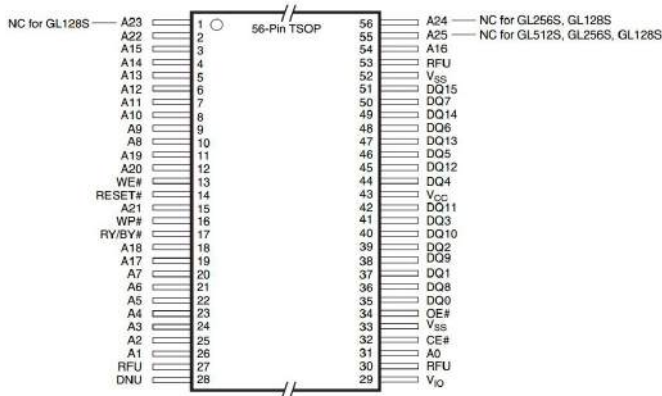
### Electrical Test (MIL-STD-883 and Manufacturer Specification)

#### Results Summary

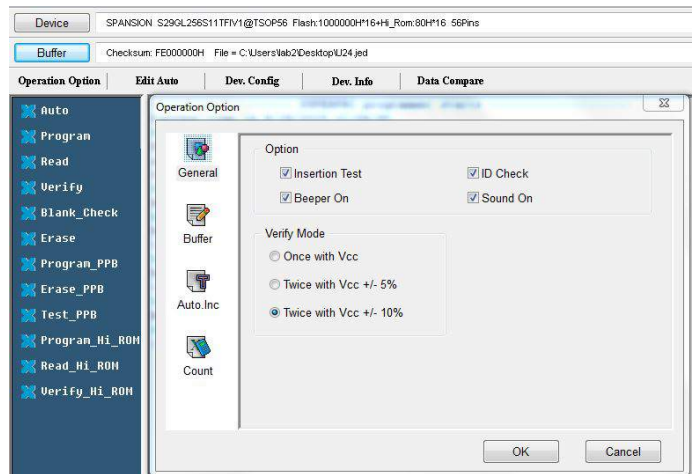
S29GL256S11TFIV10: NOR Flash Parallel 3V/3.3V 256M-bit 16M x 16 110ns 56-Pin TSOP  
 Tested 20 functionally at 25C via Memory Test: Read, Verify, and Blank Check. Passed: 20. Checksum: FE000000. Sample Programming was performed and Part's erased afterwards at 25C.

Test-Process Operation	Quantity Inspected	Pass	Fail	Date	N/A	Comments / Observations
Electrical Test (MIL-STD-883 and Manufacturer Specification)						
Memory Function Test TA = 25°C	20	20	0	2015-08-19		
<b>Equipment Used</b>	PROGRAMMER <b>Asset Tag:</b> 42 <b>Calibration Due Date:</b> Not Required					

### Images For Electrical Test.



**Figure 26. PIN DIAGRAM**



**Figure 27. S29GL256S11TFIV10 CHECK ID**

S29GL256S11TFIV10: NOR Flash Parallel 3V/3.3V 256M-bit 16M x 16 110ns  
 56-Pin  
 TSOP  
 Pin Diagram

DUT Test Features are turned on at 25C

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## Analysis Report - 2000-13153

<b>Customer Name:</b>	SAMPLE REPORT-15	<b>Purchase Order:</b>	4504435317
<b>Part Number:</b>	S29GL256S11TFIV10	<b>Lot/Date Code:</b>	1521
<b>Manufacturer:</b>	SPANSION	<b>Devices Received:</b>	50

**Figure 28.** S29GL256S11TFIV10 BLANK CHECK 10 PERCENT

Memory Test Operations was performed passed at 25C: Read, Verify, and Blank Check.  
Good!  
(with shown Vcc)

**Figure 29.** S29GL256S11TFIV10 BLANK CHECK BUFFER

DUT shown blank data buffer contents at 25C => Passed Blank Check (CS=0xFE000000)

**Prepared by:**  
Miller, David W.  
**Approved by:**  
Tang, Dan C.

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### Analysis Report - 2000-13153

<b>Customer Name:</b>	SAMPLE REPORT-15	<b>Purchase Order:</b>	4504435317
<b>Part Number:</b>	S29GL256S11TFIV10	<b>Lot/Date Code:</b>	1521
<b>Manufacturer:</b>	SPANSION	<b>Devices Received:</b>	50

**Figure 30.** S29GL256S11TFIV10 PROGRAM TRIAL BUFFER

DUT shown data buffer contents at 25C after Sample Programming was performed and Part's erased afterwards at 25C. Good!

**Figure 31.** S29GL256S11TFIV10 BLANK CHECK ERASE

DUT was programmed,erased, and re-verified Blank Check. Good!

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### Analysis Report - 2000-13153

<b>Customer Name:</b>	SAMPLE REPORT-15	<b>Purchase Order:</b>	4504435317
<b>Part Number:</b>	S29GL256S11TFIV10	<b>Lot/Date Code:</b>	1521
<b>Manufacturer:</b>	SPANSION	<b>Devices Received:</b>	50

#### Solderability Test (MIL-STD-883 Method 203.8 and J-STD-002)

##### Results Summary

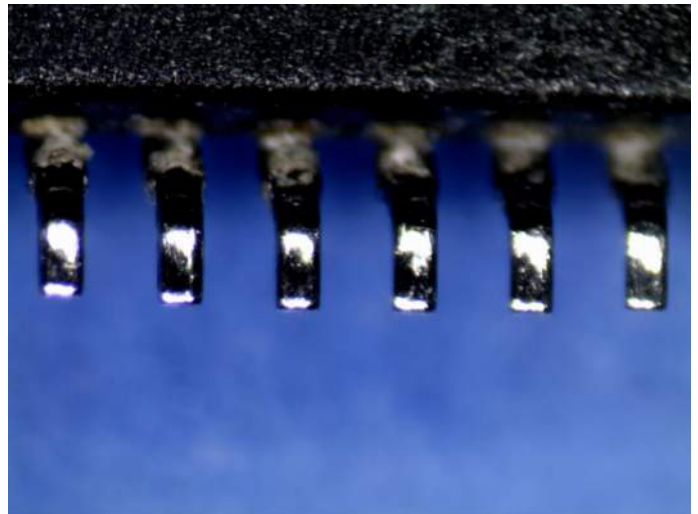
1 device from date code 1521 was tested using dip and look method. Device was inspected under 20X magnification. All leads indicated to have over 95% solder coverage. No pinholes or voids are found.

Criteria	Acceptable	Suspect	Not Acceptable	N/A	Comments / Observations
Solderability Test					
Hot Solder Dip (Destructive)	X				

#### Images For Solderability Test.



**Figure 32.** SOLDER LEADS VIEW 1



**Figure 33.** SOLDER LEADS VIEW 2

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